

# Model 40623

## Single Element Pyroelectric IR Detector with Source Follower

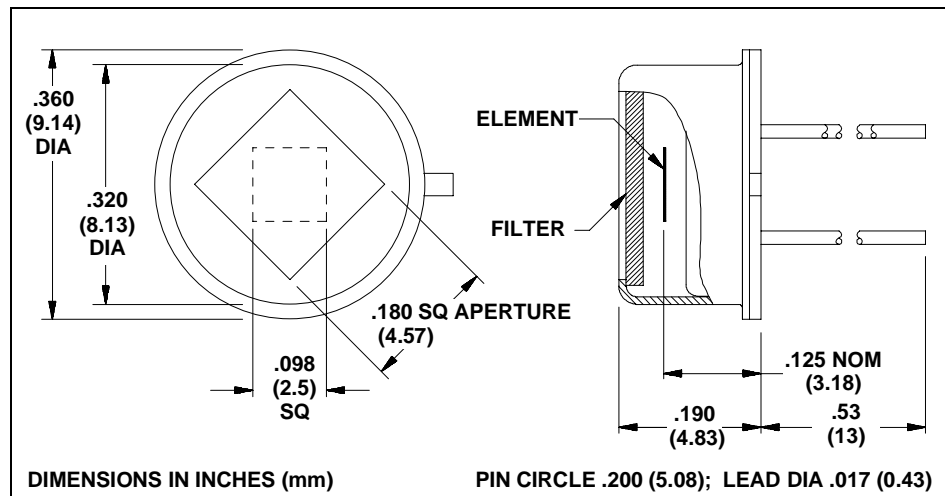


Manufactured under one or more of the following U.S. patents: 3,839,640 - 4,218,620 - 4,326,663 - 4,384,207 - 4,437,003 - 4,441,023 - 4,523,095

**Model 40623** consists of a single lithium tantalate sensing element, a  $4 \times 10^9 \Omega$  load resistor and a JFET source follower sealed into a TO-5 transistor housing with an optical filter.

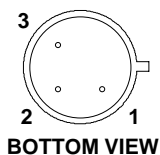
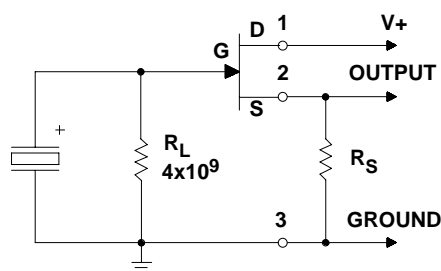
The Model 40623 differs from the Model 406 in that the frequency response has been optimized in the region of flame flicker phenomena.

A source resistor is needed to set the drain current and consequently the operating parameters of the JFET. A  $47k \Omega$  or greater value resistor is recommended.



### Applications

- Flame Detection
- Industrial Control
- Motion Sensing
- Gas Analysis
- Pyrometry
- Instrumentation
- Furnace Flame Control

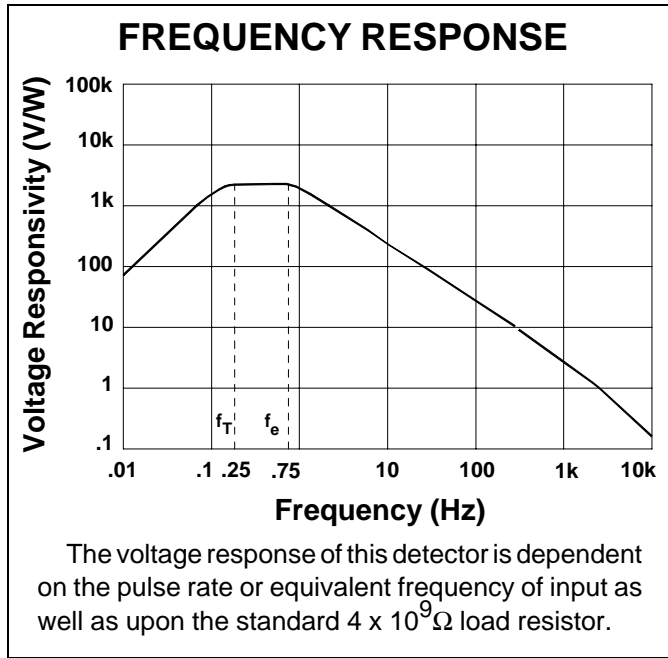
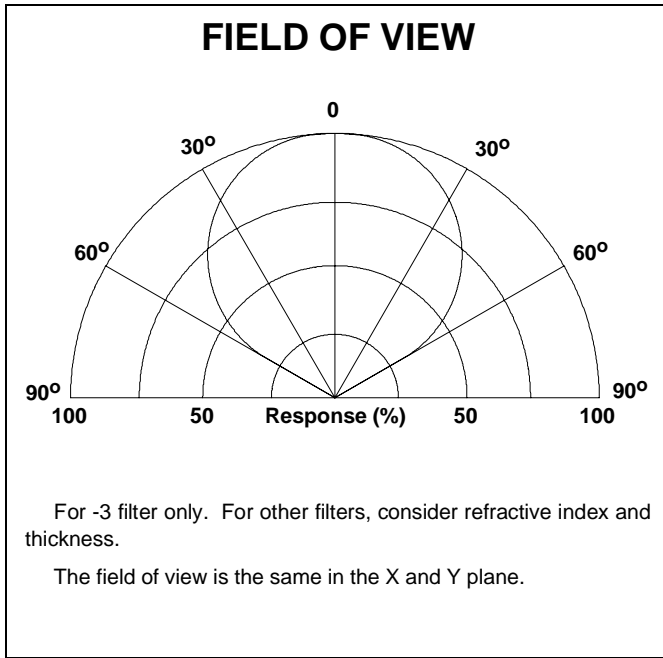


#### PIN DESIGNATIONS

1. V+
2. OUTPUT
3. GND/CASE

Characteristics	40623	Unit	Test Conditions	ELTECdata Reference
Detector Type	Single			
Element Size	2.5 x 2.5	mm		
Optical Bandwidth	0.1 to 1,000	$\mu\text{m}$	Various Filters	101
Responsivity (typ)	550	V/W	3.6 to 4.0 $\mu\text{m}$ , 3 Hz	
Noise (typ)	1.63	$\mu\text{V}/\sqrt{\text{Hz}}$	3 Hz (rms)	
NEP (typ)	$2.96 \times 10^{-9}$	$\text{W}/\sqrt{\text{Hz}}$	8 to 14 $\mu\text{m}$ , 3 Hz, 1 Hz BW	100
$D^*$ (typ)	$0.84 \times 10^8$	$\text{cm}\sqrt{\text{Hz}}/\text{W}$	8 to 14 $\mu\text{m}$ , 3 Hz, 1 Hz BW	100
Operating Voltage (min)	3	VDC	V+ to Gnd	104
Operating Voltage (max)	15			(4.1.c)
Operating Current (min)	3	$\mu\text{A}$	$R_S = 100k \Omega$	104
Operating Current (max)	12			(4.1.c)
Offset Voltage (min)	0.3	V	$R_S = 100k \Omega$	106
Offset Voltage (max)	1.2			Section B
Output Impedance	$<R_S$	$\Omega$		
Thermal Breakpoint $f_T$ (typ)	0.25	Hz		102
Electrical Breakpoint $f_e$ (typ)	0.75	Hz	$R_L = 4 \times 10^9 \Omega$	102
Recommended Operating Temp.	-10 to +50	$^\circ\text{C}$	Functional	
Storage Temperature	-55 to +125	$^\circ\text{C}$	$\Delta T < 50^\circ\text{C}/\text{min}$	
Output Protection	Do not exceed a maximum drain current of 50 $\mu\text{A}$			

Characteristics at  $25^\circ\text{C}$ , with -3 filter,  $V+ = 5 \text{ VDC}$ ,  $R_S = 100k\Omega$  unless otherwise stated. Data is established on a sample basis and is believed to be representative.



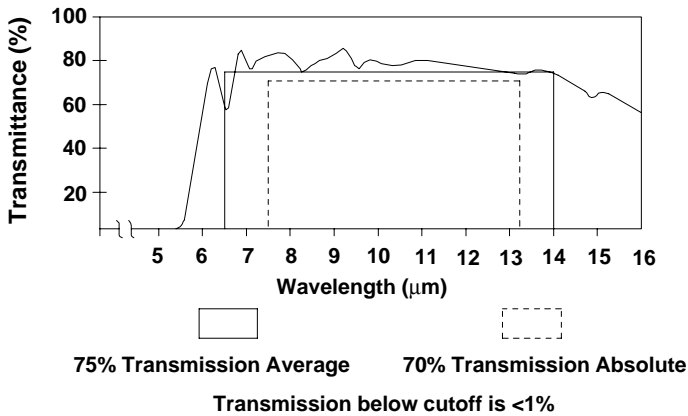
For best results, the following precautions and recommendations should be observed. (See ELTECdata # 101):

**Mounting:** Avoid mechanical stresses on case and leads.

**Soldering:** Detectors must be hand soldered to minimize the chance of destroying the internal components. Avoid machine or hot air soldering. Leave a minimum lead length of .250 inch (6.35mm). When soldering to detector leads, use a heat sink between the case and leads. Beware that the new RoHS compliant solders require a higher soldering temperature making heat sinking the detector extremely important.

**Static Discharge:** Protect detectors from electrostatic charges.

#### Transmission Characteristics of -3 Filter (HP-7)



For information on other standard filters available, refer to ELTECdata # 101

**Thermal Shock:** Temperature changes and rate of change must be kept to a minimum (<50C°/min.) to prevent damage.

**Noise:** As a resolution or lower information limit, noise is established not only by the detector. Other noise sources are:

- Radiated and conducted RF signals
- Subsequent amplification or signal conditioning stages
- Power supply noise
- Components, such as high value resistors and capacitors (tantalum or electrolytic)
- Mechanical contacts and weak solder joints
- Shock and vibration excited microphonics
- Outside thermal influences on the detector other than the desired infrared input, i.e. drafts

All of these noise sources should be considered carefully when the information signal is <1mV.

**Light Leakage:** Slight sensitivity to visible light leaking through the base glass-to-metal seal may be observed.

**Optical Design:** Use of a detector with a filter in an optical system may require consideration of the image displacement toward the filter. This displacement (s) caused by the insertion of a planoparallel plate (filter thickness = t; refractive index = N) is given by  $s = (t / N) (N - 1)$ .

**NOTICE:** The information provided herein is believed to be reliable. However, ELTEC Instruments, Inc. assumes no responsibility for inaccuracies or omissions. Due to industry components being incorporated into ELTEC's devices and ELTEC continually striving for product improvement, specifications may change without notice.